AMENDMENTS TO THE CLAIMS

Please amend the claims as follows:

- 1. (Currently amended) An electromagnetic wave shielding material which comprises a transparent substrate, physically developed nuclei laid thereon, a layer of physically developed silver having a fine line pattern formed on said nuclei, and a metal film plated on said physically developed silver, wherein the fine line pattern has a line width of 40 μm or less, a total luminous transmittance of 50% or higher, and a surface resistance of 10 ohm/□ or less.
- 2. (Currently amended) The electromagnetic wave shielding material according to Claim 1, wherein the fine line pattern has a thickness of 15 μm-or less and a line width of 40 μm or less, a total luminous transmittance of 50% or higher, and a surface resistance of 10 ohm/□ or less.
- 3. (Previously presented) The electromagnetic wave shielding material according to Claim 2, wherein the total luminous transmittance is 60% or higher.
- 4. (Previously presented) The electromagnetic wave shielding material according to Claim 2, wherein the surface resistance is 7 ohm/□ or less.
- 5. (Previously presented) The electromagnetic wave shielding material according Claim 2, wherein the thickness of the fine line pattern is 0.5 to 15 μm.
- 6. (Previously presented) The electromagnetic wave shielding material according to Claim 5, wherein the thickness of the fine line pattern is 2 to 12 μ m.
- 7. (Previously presented) The electromagnetic wave shielding material according to Claim 2, wherein the line width of the fine line pattern is 1 to 40 μ m.
- 8. (Previously presented) The electromagnetic wave shielding material according to Claim 1, wherein the plating is an electrolytic plating.

- 9. (Previously presented) The electromagnetic wave shielding material according to Claim 1, wherein the plating is at least one kind of plating selected from copper and nickel.
- 10. (Allowed) A process for preparing an electromagnetic wave shielding material which comprises exposing a light-sensitive material having a physical development nuclei layer and a silver halide emulsion layer on a transparent substrate in this order, precipitating metal silver with a pattern having an optional fine line onto the physical development nuclei layer by physical development, then,

removing a layer provided on the physical development nuclei layer, and subjecting to plating a metal with the use of the physically developed metal silveras a catalytic nucleus to obtain an electromagnetic wave shielding material having a fine line pattern.

- 11. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 10, wherein the fine line pattern after the metal plating has a thickness of 15 μm or less and a line width of 40 μm or less, a total luminous transmittance of 50% or higher, and a surface resistance of 10 ohm/□ or less.
- 12. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 11, wherein the total luminous transmittance is 60% or higher.
- 13. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 11, wherein the surface resistance is 7 ohm/ \square or less.
- 14. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 11, wherein after the metal plating the thickness of the fine line pattern is 0.5 to $15 \mu m$.
- 15. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 14, wherein after the metal plating the thickness of the fine line pattern is 2 to $12 \mu m$.

- 16. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 11, wherein after the metal plating the line width of the fine line pattern is 1 to $40 \mu m$.
- 17. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 10, wherein the plating is an electrolytic plating.
- 18. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 10, wherein the plating is at least one kind of plating selected from copper and nickel.
- 19. (Allowed) The process for preparing an electromagnetic wave shielding material according to Claim 18, wherein an electrolytic plating is carried out by dipping a transparent substrate on which a physically developed silver has been formed in a bath containing copper sulfate and sulfuric acid as main components with a current density of 1 to 20 ampere/dm² at 10 to 40°C.